

# **TK55A10J1**

### **Switching Regulator Applications**

· High-Speed switching

• Low gate charge: Q<sub>g</sub> = 110 nC (typ.)

• Low drain-source ON resistance:  $R_{DS}(ON) = 8.4 \text{ m}\Omega$  (typ.)

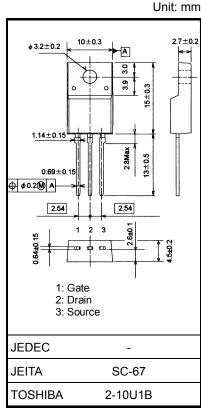
• High forward transfer admittance:  $|Y_{fs}| = 110 \text{ S (typ.)}$ 

Low leakage current: I<sub>DSS</sub> = 10 μA (max) (V<sub>DS</sub> = 100 V)

• Enhancement mode:  $V_{th}$  = 1.1 to 2.3 V ( $V_{DS}$  = 10 V,  $I_D$  = 1 mA)

## **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Drain-source voltage	)	V <sub>DSS</sub>	100	V	
Drain-gate voltage (F	R <sub>GS</sub> = 20 kΩ)	$V_{DGR}$	100	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	I <sub>D</sub>	55	А	
	Pulse (Note 1)	I <sub>DP</sub>	210		
Drain power dissipat	ion (Tc = 25°C)	PD	45	W	
Single pulse avalance	the energy (Note 2)	E <sub>AS</sub>	382	mJ	
Avalanche current		I <sub>AR</sub>	55	Α	
Repetitive avalanche	e energy (Note 3)	E <sub>AR</sub>	3.0	mJ	
Channel temperature	Э	T <sub>ch</sub>	150	°C	
Storage temperature	range	T <sub>stg</sub>	-55 to 150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.78	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel and lead temperatures do not exceed 150°C.

Note 2:  $V_{DD} = 25$  V,  $T_{ch} = 25$ °C, L = 200  $\mu H$ ,  $I_{AR} = 55$  A,  $R_G = 1\Omega$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.

# Electrical Characteristics (Ta = 25°C)

Chara	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-OFF cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V	_	_	10	μА
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$		_		V
		V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	55	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.1	_	2.3	V
Drain-source ON resistance		R <sub>DS</sub> (ON)	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 27A	_	9.0	12.0	- mΩ
			$V_{GS} = 10 \text{ V}, I_D = 27A$	_	8.4	10.5	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_D = 27 \text{ A}$	55	110		S
Input capacitance	Input capacitance C <sub>iss</sub>			_	5700		pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 10V, V_{GS} = 0 V, f = 1 MHz$	_	390		
Output capacitance		C <sub>oss</sub>			1000		
Switching time	Rise time	t <sub>r</sub>	$\begin{array}{c} 10 \text{ V} \\ \text{VGS} \\ 0 \text{ V} \\ \end{array} \begin{array}{c} \text{I}_D = 27 \text{ A} \\ \text{O VOUT} \\ \end{array} \\ \begin{array}{c} \text{CI} \\ \text{S} \\ \text{V} \\ \text{DD} \approx 50 \text{ V} \\ \end{array}$ Duty $\leq 1\%$ , $t_W = 10 \mu\text{s}$	_	7	_	
	Turn-ON time	t <sub>on</sub>		_	30		ns
	Fall time	t <sub>f</sub>		_	20		i iis
	Turn-OFF time	t <sub>off</sub>		_	130		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \approx 80 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 55 \text{A}$	_	63	_	
			$V_{DD} \approx 80 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 55 \text{A}$		110		
Gate-source charge 1		Q <sub>gs1</sub>	$V_{DD} \approx 80 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 55\text{A}$	_	17	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	32	_	
Gate switch charge		Q <sub>SW</sub>		_	38	_	

## **Source-Drain Ratings and Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{DR}$	_	_	_	55	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	220	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 55 A, V <sub>GS</sub> = 0 V	_	-0.9	-1.2	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 55 A, V <sub>GS</sub> = 0 V,	_	67	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 50 A/μs		84	_	nC

## Marking

